



Development status of the electrostatic accelerometer for the GRACE-FO mission

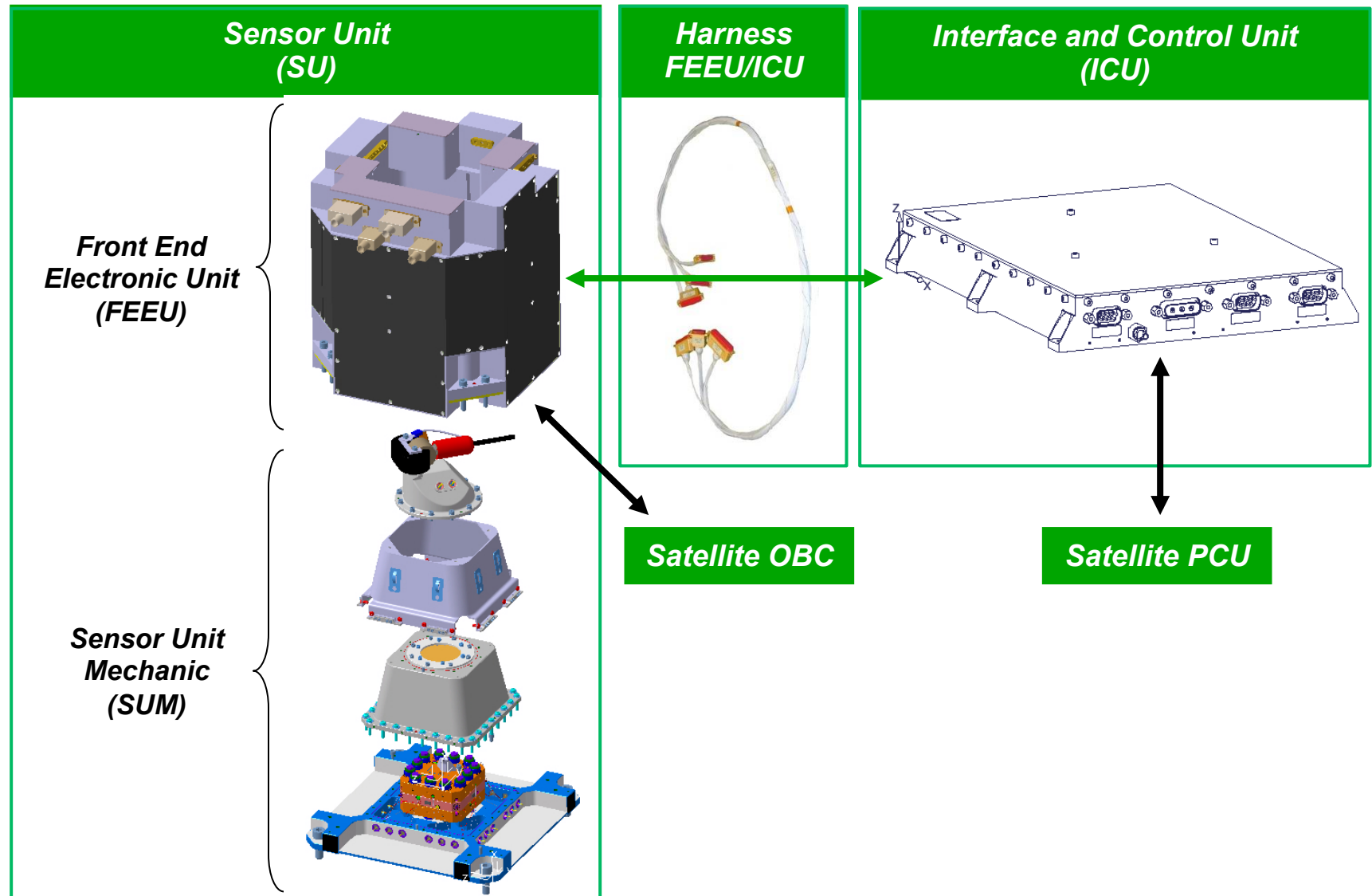
B. Foulon, B. Christophe, D. Boulanger, F. Liorzou and V. Lebat

Austin, October 23, 2013

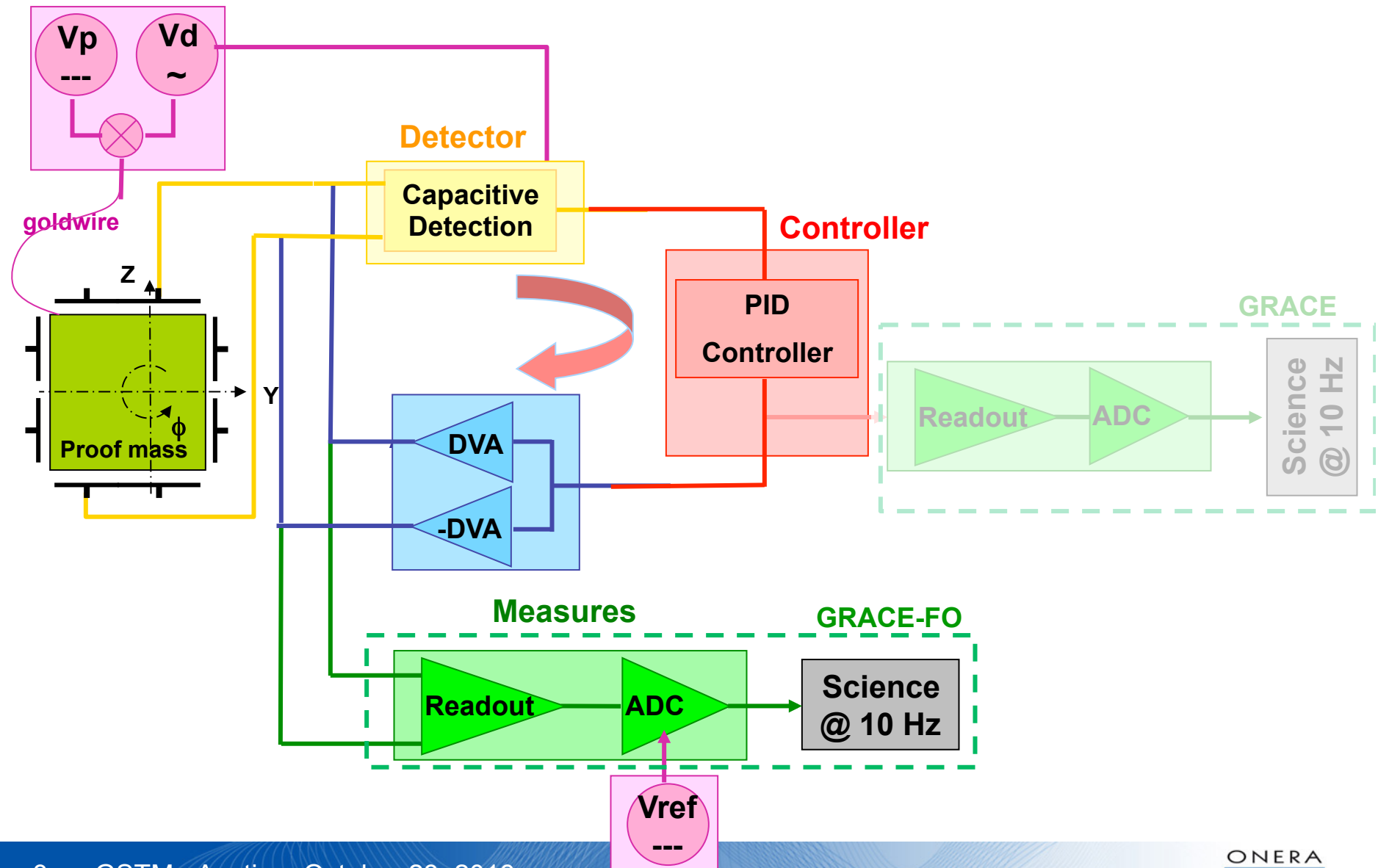


r e t u r n o n i n n o v a t i o n

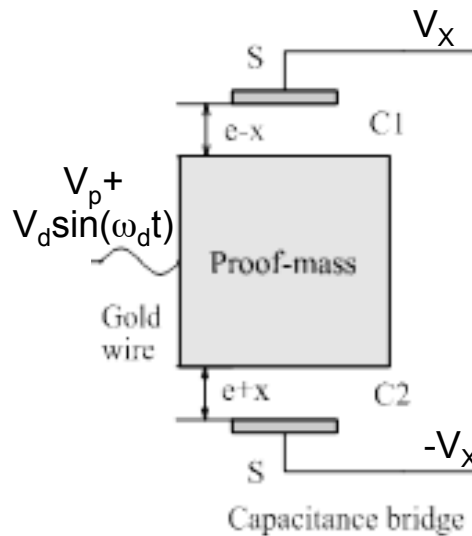
Accelerometer Description



Accelerometer principle of operation (1/2)

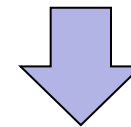


Accelerometer principle of operation (2/2)



Electrostatic force

$$F = F_1 - F_2 = \frac{1}{2} \left[\frac{\partial C_2}{\partial x} (V_X - V_p - V_d \sin(\omega_d t))^2 \right] - \frac{1}{2} \left[\frac{\partial C_1}{\partial x} (V_X + V_p + V_d \sin(\omega_d t))^2 \right]$$



$$a_X = \frac{2\epsilon S}{me^2} \left(V_p^2 + \frac{V_d^2}{2} \right) \frac{x}{e} - \frac{2\epsilon S}{me^2} V_p V_X + \frac{2\epsilon S}{me^2} V_X^2 \frac{x}{e}$$

Capacitive Detection

$$\Delta C = \frac{2\epsilon S}{e} x$$

Electrostatic
stiffness

Electrostatic
gain

Cubic
term

The measurement

Accelerometer Mode

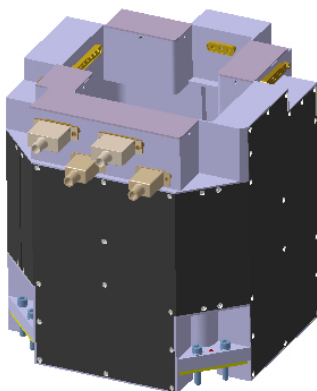
Large Range Mode (LRM) for acquisition : $V_p = 40 \text{ V}$ and $V_d = 1,25 \text{ Vrms}$

Nominal Range Mode (NRM) for science : $V_d = 10 \text{ V}$ and $V_p = 5 \text{ Vrms}$

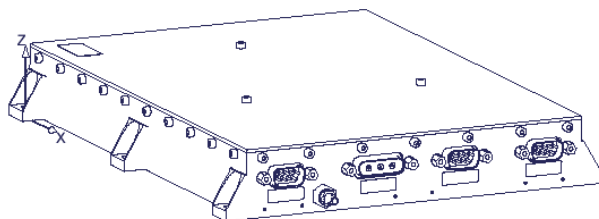
Electronics Description



FEEU

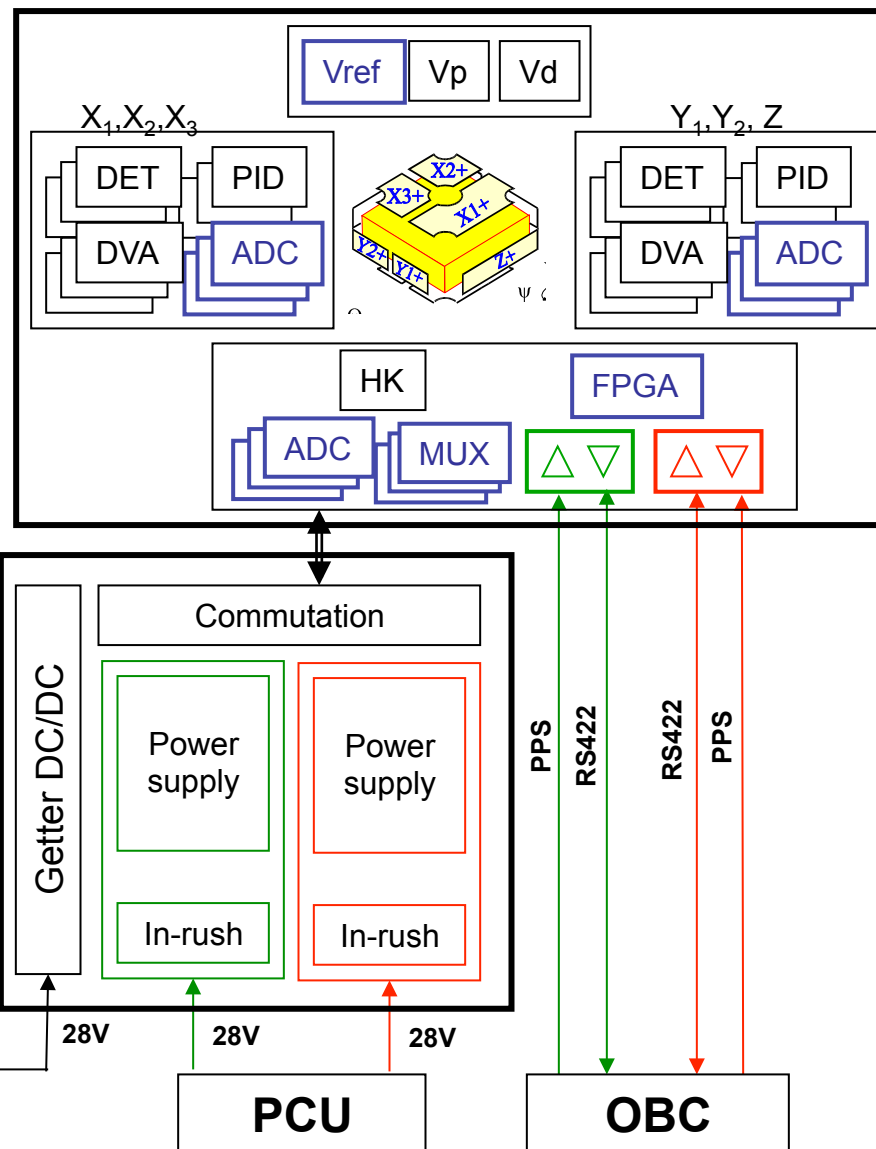


ICU



S/C

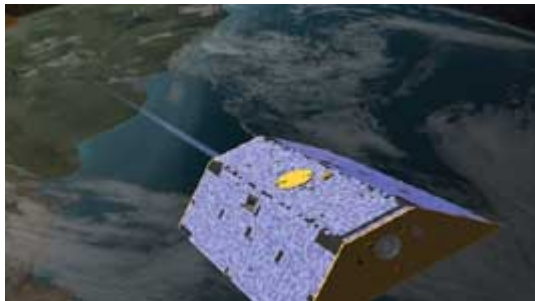
**Skin
connector**



Requirements

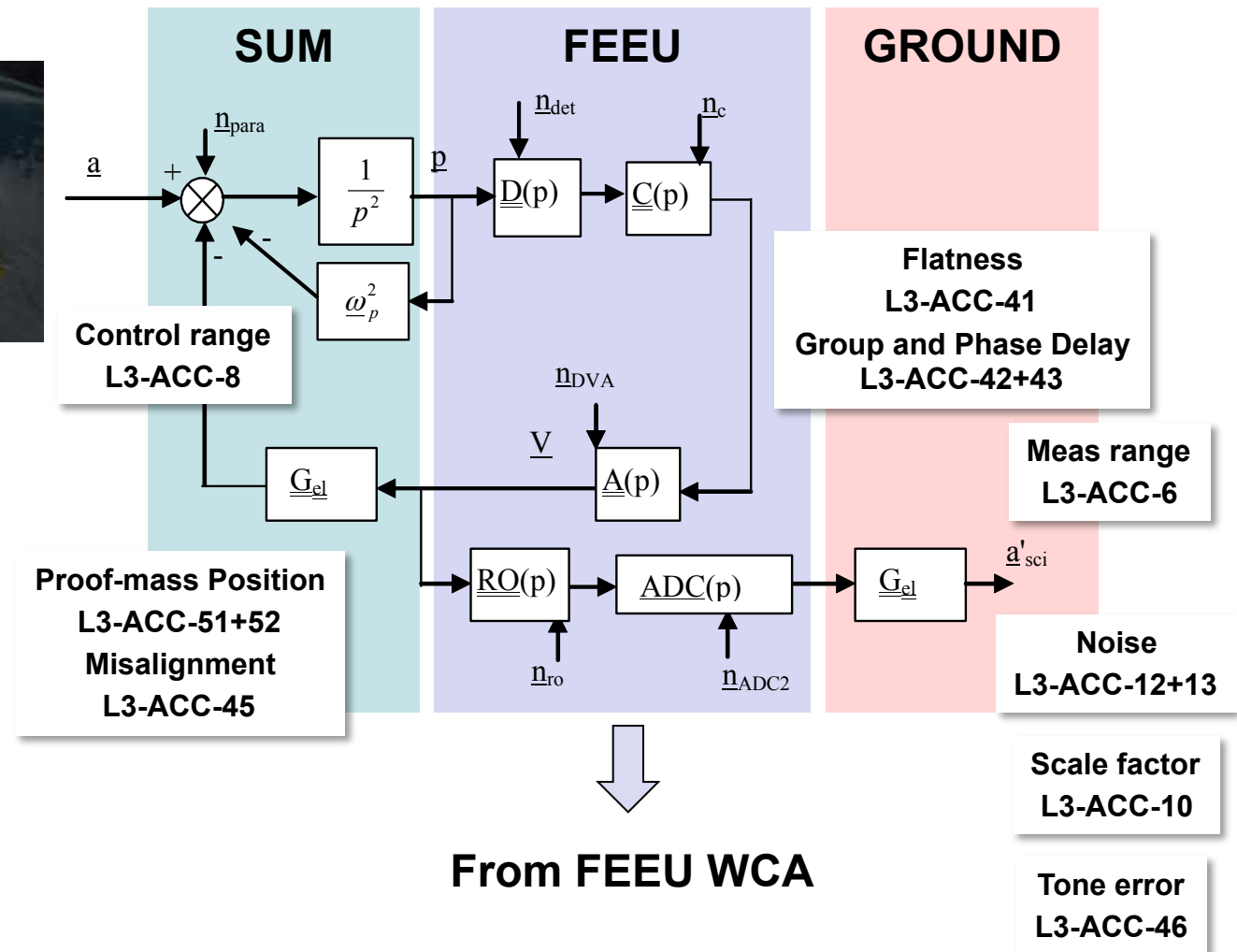


Environment Drag



$$Y/Z \pm 5 \times 10^{-5} \text{ m/s}^2$$

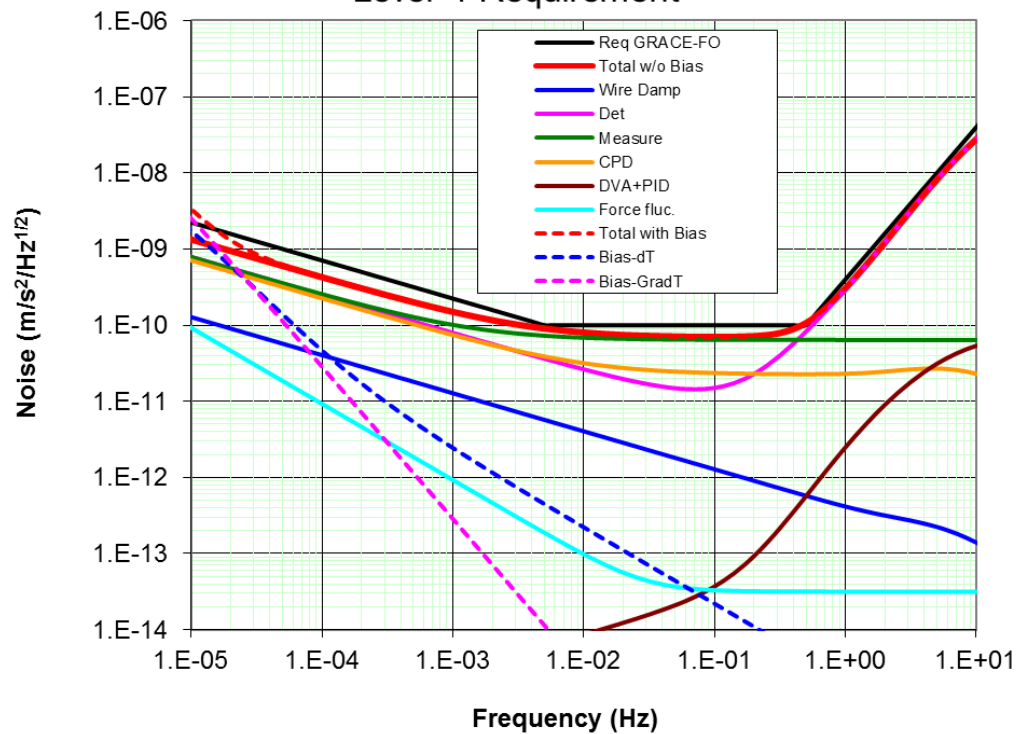
$$X \pm 5 \times 10^{-4} \text{ m/s}^2$$



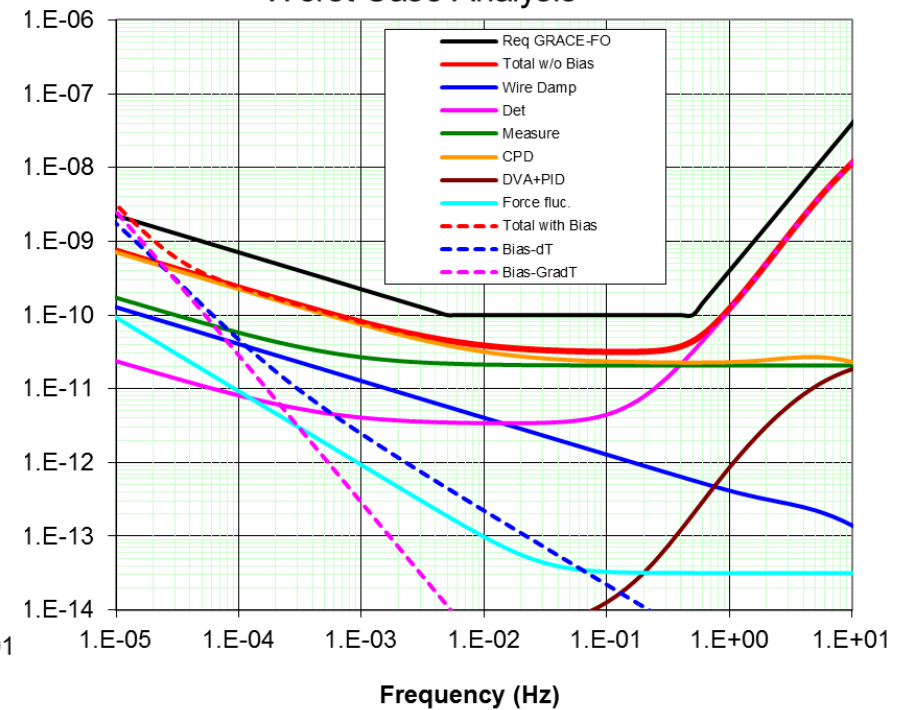
Noise Performance



Noise of SuperSTAR along Z axis
Level 4 Requirement



Noise of SuperSTAR-FO along Z axis
Worst Case Analysis



Requirement achieved

Scale factor knowledge



Level 4 Requirement

Knowledge on ground	At accelerometer level			At contributor level			unit
	X	Y	Z	X	Y	Z	
Gap knowledge	1.67%	1.14%	1.14%	0.5	1	1	μm
Mass knowledge	0.28%	0.28%	0.28%	0.2	0.2	0.2	g
Electrode surface knowledge	0.69%	1.41%	1.41%	0.05	0.07	0.07	mm
Polarization voltage knowledge	0.10%	0.10%	0.10%	0.100%	0.100%	0.100%	% of Vp
Reference voltage knowledge	0.10%	0.10%	0.10%	0.100%	0.100%	0.100%	% of Vref
Contact potential difference and patch effect	0.15%	0.15%	0.15%	0.015	0.015	0.015	V
DVA bias	0.02%	0.02%	0.02%	0.002	0.002	0.002	V
Read-out amplifier gain	0.50%	0.50%	0.50%	0.50%	0.50%	0.50%	%
ADC gain	0.05%	0.05%	0.05%	0.05%	0.05%	0.05%	%
Total	1.90%	1.92%	1.92%				
Requirement	2%	2%	2%				

WCA

Knowledge on ground	At accelerometer level			At contributor level			unit
	X	Y	Z	X	Y	Z	
Gap knowledge	1.67%	1.14%	1.14%	0.5	1	1	μm
Mass knowledge	0.28%	0.28%	0.28%	0.2	0.2	0.2	g
Electrode surface knowledge	0.69%	1.41%	1.41%	0.05	0.07	0.07	mm
Polarization voltage knowledge	0.02%	0.02%	0.02%	0.019%	0.019%	0.019%	% of Vp
Reference voltage knowledge	0.02%	0.02%	0.02%	0.019%	0.019%	0.019%	% of Vref
Contact potential difference and patch effect	0.15%	0.15%	0.15%	0.015	0.015	0.015	V
DVA bias	0.00%	0.00%	0.01%	2.89E-04	3.54E-04	5.00E-04	V
Read-out amplifier gain	0.43%	0.43%	0.24%	0.43%	0.43%	0.24%	%
ADC gain	0.05%	0.05%	0.05%	0.050%	0.050%	0.050%	%
Total	1.88%	1.90%	1.86%				
Requirement	2%	2%	2%				

Requirement achieved

Scale factor stability



Scale factor stability over **1 month (hypothesis)**

Temperature range FA [5-40]°C : need a correction from ground characterisation

Stability over 1 month	At accelerometer level			At accelerometer level			At contributor level			
	X	Y	Z	X	Y	Z	X	Y	Z	unit
Variation between 0°C and 40°C, measured at 20°C	20 °C	corrected at	1 °C	20 °C	corrected at	1 °C				
Gap thermal variation	0.00172%	0.00172%	0.00172%	0.00172%	0.00172%	0.00172%	8.6	8.6	8.6	ppm/°C
Error on Gap thermal variation	0.00344%	0.00344%	0.00344%	0.00344%	0.00344%	0.00344%	0.86	0.86	0.86	ppm/°C
Electrode surface thermal variation	0.00006%	0.00006%	0.00006%	0.00006%	0.00006%	0.00006%	0.03	0.03	0.03	ppm/°C
Polarization voltage thermal variation	0.00050%	0.00050%	0.00050%	0.00042%	0.00042%	0.00042%	4.20	4.20	4.20	ppm/°C
Error on Polarization voltage thermal variation	0.00100%	0.00100%	0.00100%	0.00084%	0.00084%	0.00084%	0.42	0.42	0.42	ppm/°C
Reference voltage thermal variation	0.00050%	0.00050%	0.00050%	0.00043%	0.00043%	0.00043%	4.30	4.30	4.30	ppm/°C
Error on Reference voltage thermal variation	0.00100%	0.00100%	0.00100%	0.00086%	0.00086%	0.00086%	0.43	0.43	0.43	ppm/°C
Contact potential difference thermal variation	0.00400%	0.00400%	0.00400%	0.00400%	0.00400%	0.00400%	20	20	20	µV/°C
DVA bias thermal variation	0.00010%	0.00010%	0.00010%	0.00004%	0.00005%	0.00007%	3.83	4.69	6.64	µV/°C
Error on DVA bias thermal variation	0.00020%	0.00020%	0.00020%	0.00008%	0.00009%	0.00013%	0.383	0.469	0.664	µV/°C
Read-out amplifier gain thermal variation	0.00050%	0.00050%	0.00050%	0.00003%	0.00003%	0.00001%	0.26	0.26	0.14	ppm/°C
Error on Read-out amplifier gain thermal variation	0.00100%	0.00100%	0.00100%	0.00005%	0.00005%	0.00003%	0.026	0.026	0.014	ppm/°C
ADC gain thermal variation	0.00050%	0.00050%	0.00050%	0.00030%	0.00030%	0.00030%	3	3	3	ppm/°C
Error on ADC gain thermal variation	0.00100%	0.00100%	0.00100%	0.00060%	0.00060%	0.00060%	0.3	0.3	0.3	ppm/°C
Total thermal sensitivity	0.006%	0.006%	0.006%	0.006%	0.006%	0.006%				
Ageing over	1	month(s)		1	months					
Polarization voltage ageing	0.00400%	0.00400%	0.00400%	0.00320%	0.00320%	0.00320%	0.0032%	0.0032%	0.0032%	%/Month
Reference voltage ageing	0.00400%	0.00400%	0.00400%	0.00320%	0.00320%	0.00320%	0.0032%	0.0032%	0.0032%	%/Month
Contact potential difference ageing	0.00100%	0.00100%	0.00100%	0.00100%	0.00100%	0.00100%	100	100	100	µV/Month
DVA bias ageing	0.00010%	0.00010%	0.00010%	0.00000%	0.00000%	0.00001%	3.75E-01	4.60E-01	6.50E-01	µV/Month
Read-out amplifier gain ageing	0.00500%	0.00500%	0.00300%	0.00480%	0.00480%	0.00270%	48	48	27	ppm/Month
Total ageing	0.008%	0.008%	0.006%	0.007%	0.007%	0.005%				
Total	0.010%	0.010%	0.009%	0.009%	0.009%	0.008%				
Requirement	1%	0.20%	0.01%	1%	0.20%	0.01%				

Requirement achieved

For longer duration, ageing Vp, Vref and Readout Gain limit the performance

Tone error



Worst Case Analysis

Tone error	At accelerometer level			At contributor level			
	X	Y	Z	X	Y	Z	unit
Variation of temperature	0.1 °C	over one orbit					
Electronic bias							
Detector bias thermal variation	1.39E-10	2.38E-12	2.38E-12	30	30	30	μV/°C
Electrode surface thermal variation	8.49E-12	1.98E-13	1.98E-13	0.03	0.03	0.03	ppm/°C
Contact potential difference thermal variation	9.06E-11	2.11E-12	2.11E-12	2.00	2.00	2.00	μV/°C
Read-out amplifier bias thermal variation	2.08E-10	4.35E-12	2.38E-12	4.60	4.12	2.25	μV/°C
ADC bias thermal variation	1.43E-10	3.34E-12	3.34E-12	2.00	2.00	2.00	μV/°C
Total Electronic tone error	3.02E-10	6.35E-12	5.19E-12				
Parasitic acceleration							
Gold Wire stiffness thermal variation	3.87E-10	1.28E-11	1.28E-11	4.40E-04	4.40E-04	4.40E-04	ppm/°C
Radiometer Effect	1.20E-14	3.10E-15	3.10E-15	1.90E-13	4.90E-14	4.90E-14	m/s ² /°C
Radiation pressure	2.40E-15	6.01E-16	6.01E-16	3.80E-14	9.50E-15	9.50E-15	m/s ² /°C
Magnetism through thermal variation	2.70E-20	2.70E-20	2.70E-20	2.70E-19	2.70E-19	2.70E-19	m/s ² /°C
Magnetism through Earth magnetism variation	2.10E-13	2.10E-13	2.10E-13	2.10E-13	2.10E-13	2.10E-13	m/s ² /°C
Lorentz force	7.00E-15	9.70E-15	9.70E-15	7.00E-14	9.70E-14	9.70E-14	m/s ² /°C
Total Parasitic acceleration tone error	3.87E-10	1.28E-11	1.28E-11				
Total Tone error	4.91E-10	1.43E-11	1.38E-11				
Requirement	4.00E-12	4.00E-12	4.00E-12				

Requirement not fully achieved



Resting point estimation of gold wire
1 mm / 25 mm



Bias thermal sensitivity

GRACE

$$x : 2.7 \times 10^{-8} \text{ ms}^{-2} / ^\circ\text{C}$$

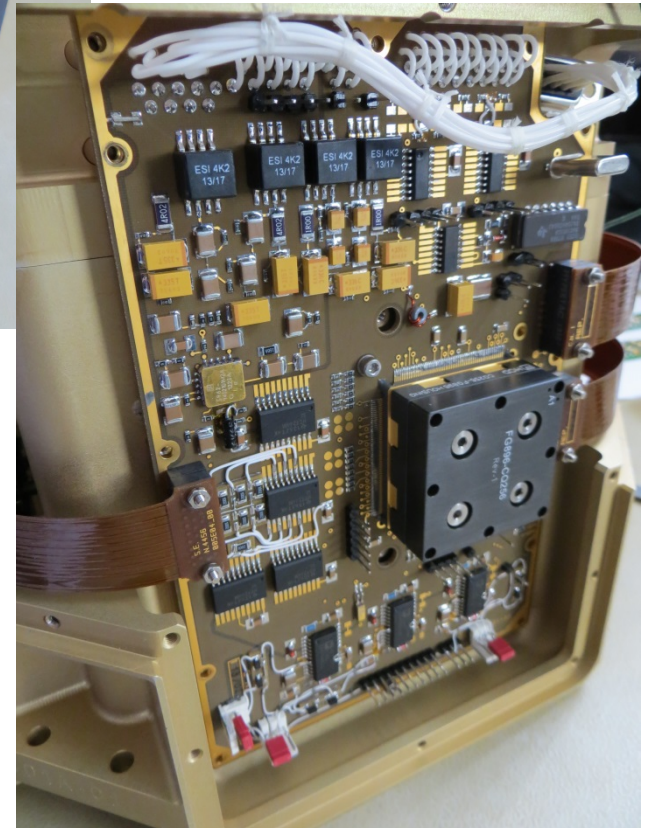
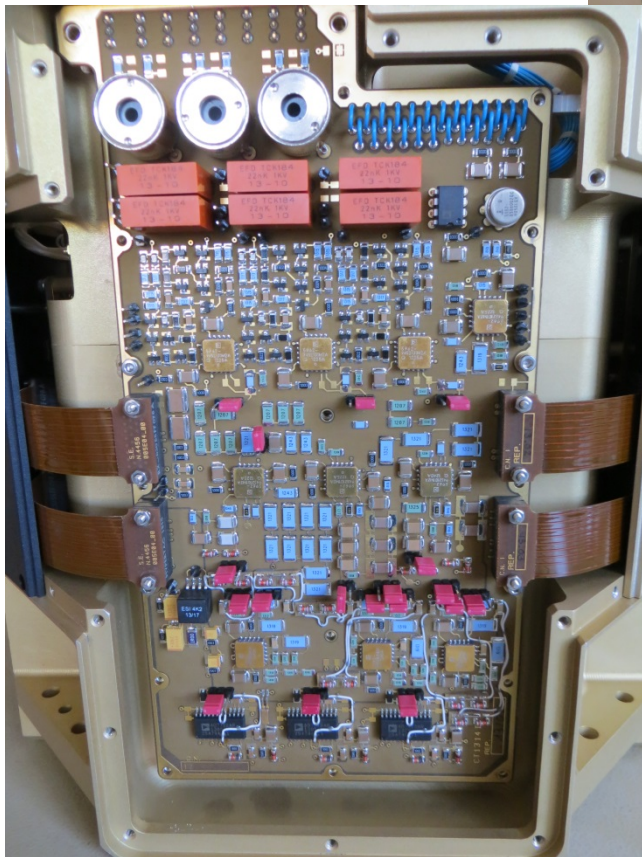
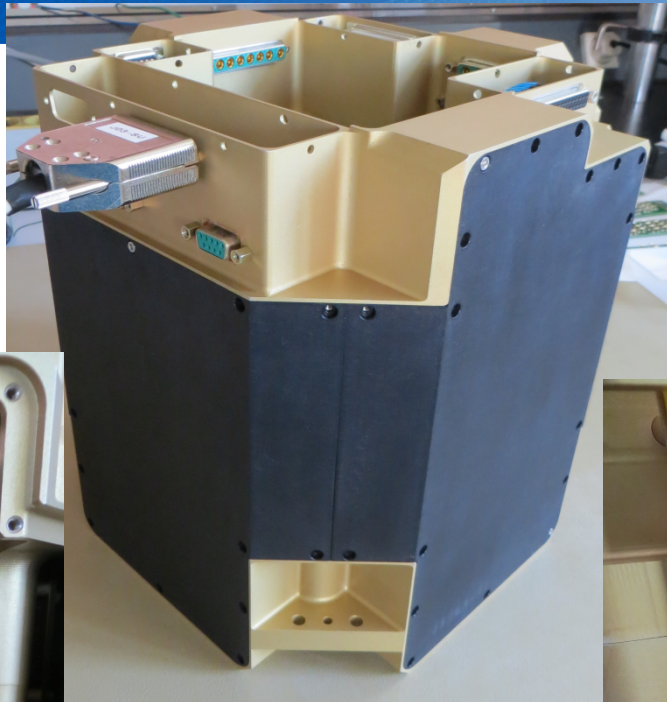
$$y, z : 5.7 \times 10^{-9} \text{ ms}^{-2} / ^\circ\text{C}$$

$$x : 4.9 \times 10^{-9} \text{ ms}^{-2} / ^\circ\text{C}$$

$$y, z : 1.4 \times 10^{-10} \text{ ms}^{-2} / ^\circ\text{C}$$

GRACE-FO

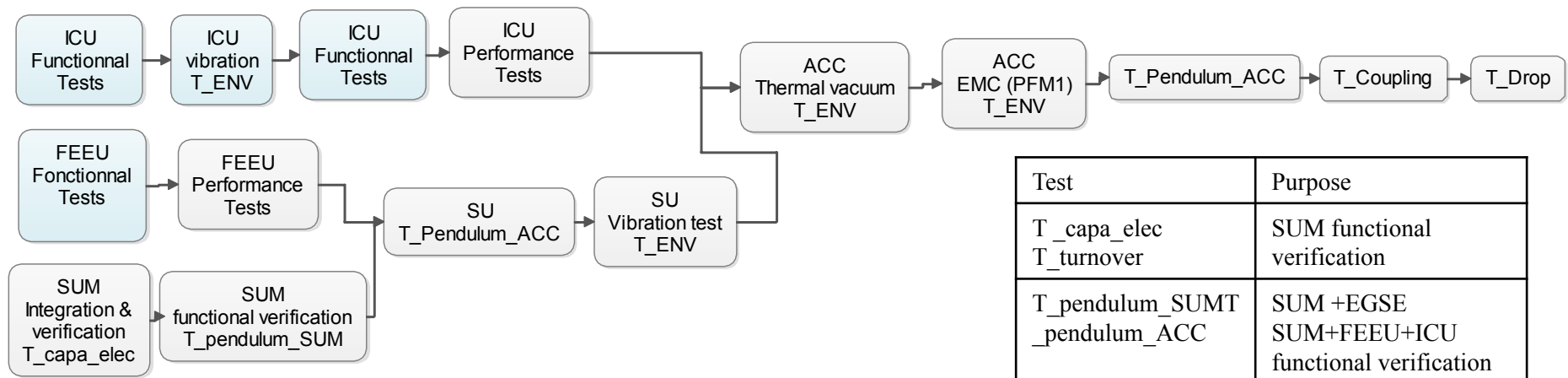
FEEU EM



Assembly, Integration and Validation Tests



AIV Flow

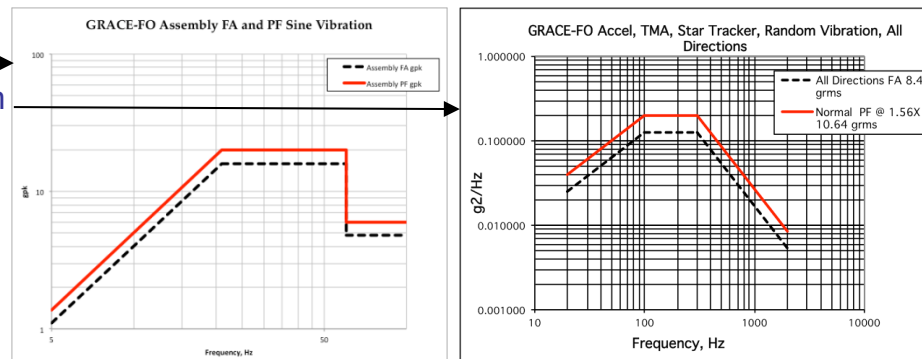


Test	Purpose
T_capa_elec T_turnover	SUM functional verification
T_pendulum_SUMT _pendulum_ACC	SUM +EGSE SUM+FEEU+ICU functional verification
T_ENV	Vibration, thermal cycling and EMC tests
T_coupling	Scale factor K calibration and Non linearity K2 verification
T_drop	Drop Tower test Flight configuration (X axis) Bias estimation

Environmental testing requirements → ERD

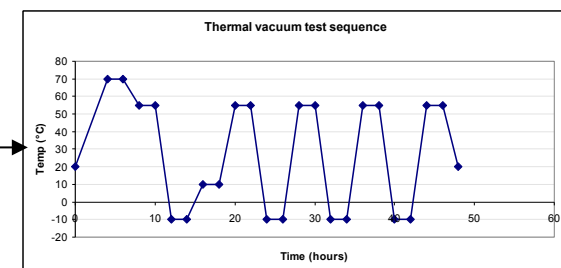
• Vibration

Sinus
Random
Shock



• Thermal vacuum

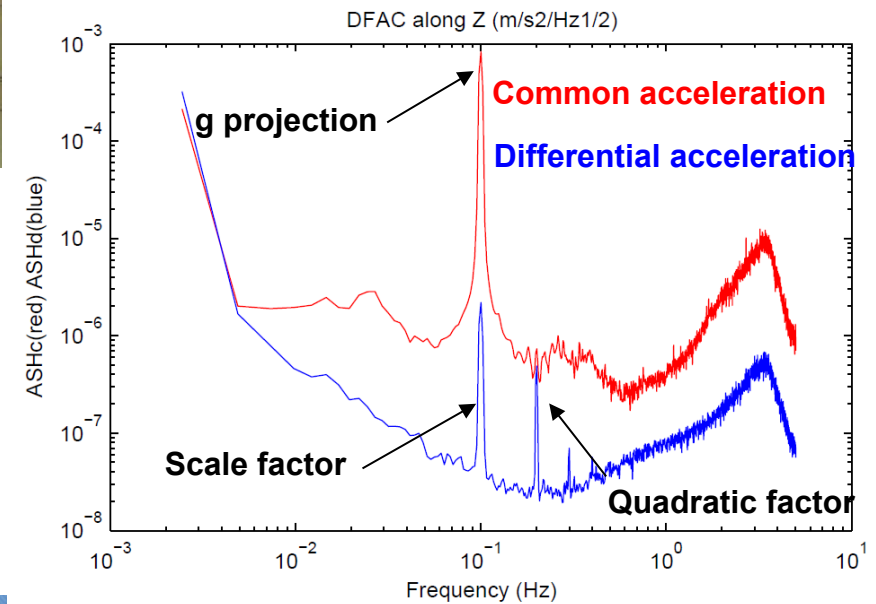
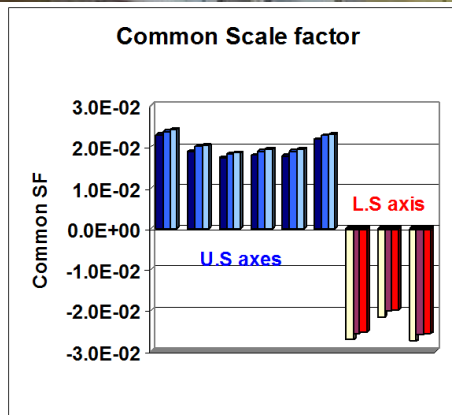
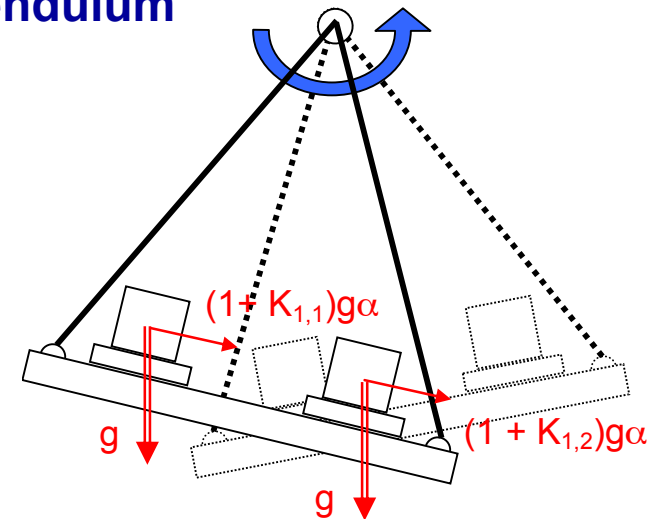
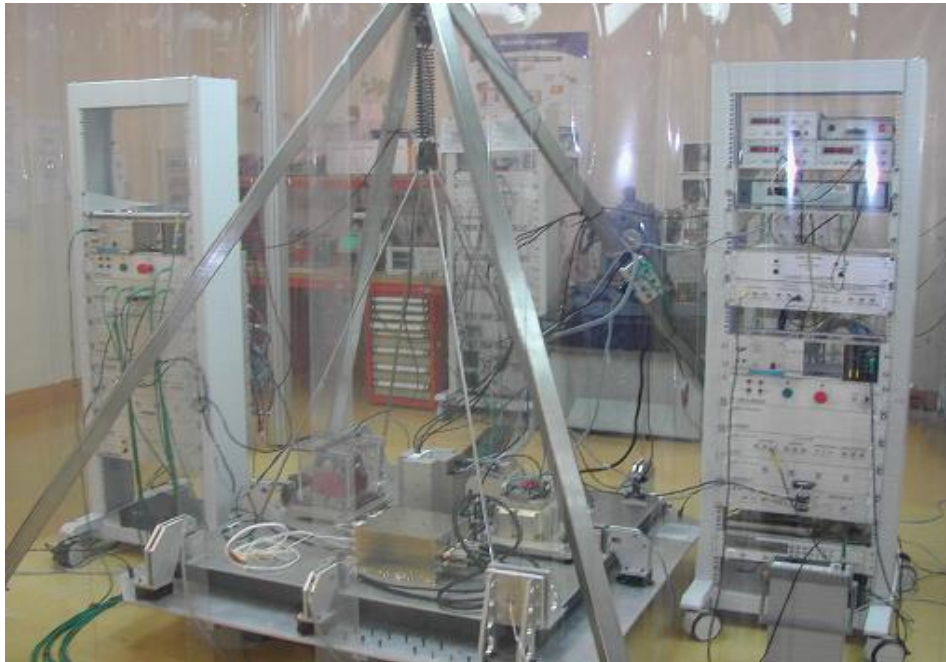
• EMC



Electrostatic accelerometer – Testing : GOCE REX



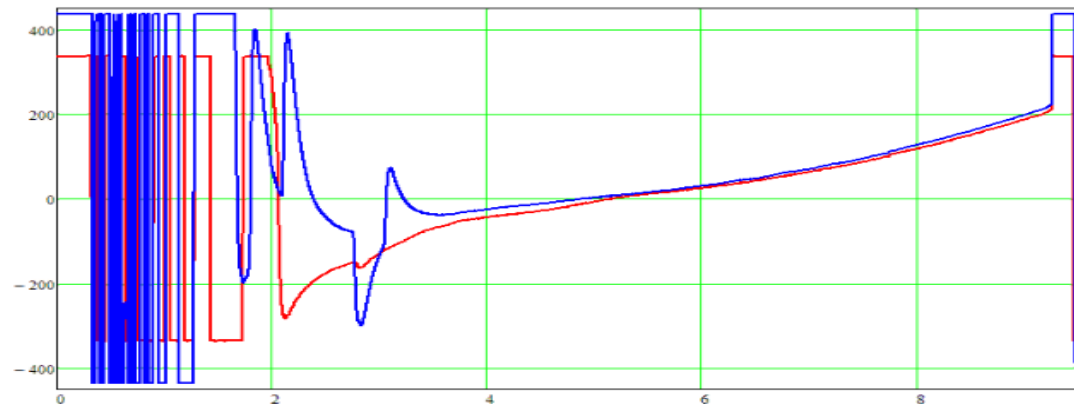
Functional and performance verification on pendulum



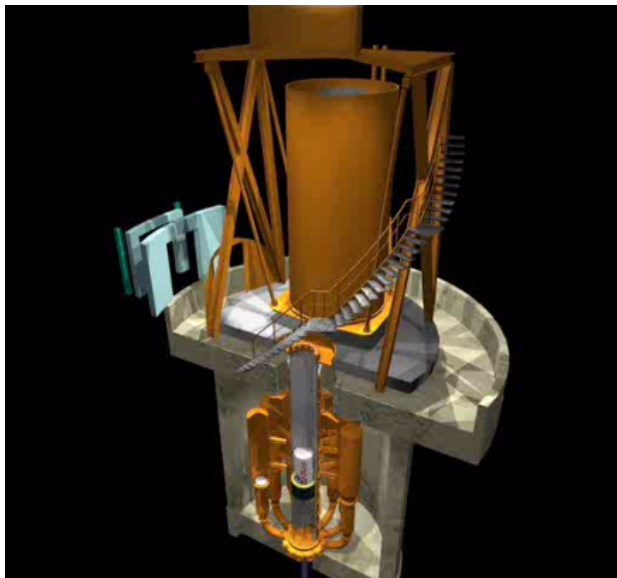


Catapult test of MICROSCOPE SUQM – drop n°61

Contribution from H. Selig (ZARM)



Slow motion (speed/2)



Schedule

